

INTERNATIONAL STANDARD

NORME INTERNATIONALE

BASIC EMC PUBLICATION
PUBLICATION FONDAMENTALE EN CEM

**Electromagnetic compatibility (EMC) –
Part 4-6: Testing and measurement techniques – Immunity to conducted
disturbances, induced by radio-frequency fields**

**Compatibilité électromagnétique (CEM) –
Partie 4-6: Techniques d'essai et de mesure – Immunité aux perturbations
conduites, induites par les champs radioélectriques**

<https://standards.iteh.ai/standards/iec/91785433-7885-40d2-8de0-629b7f8e82f8/iec-61000-4-6-2003>

WILEY
Preview





THIS PUBLICATION IS COPYRIGHT PROTECTED

Copyright © 2006 IEC, Geneva, Switzerland

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from either IEC or IEC's member National Committee in the country of the requester.

If you have any questions about IEC copyright or have an enquiry about obtaining additional rights to this publication, please contact the address below or your local IEC member National Committee for further information.

Droits de reproduction réservés. Sauf indication contraire, aucune partie de cette publication ne peut être reproduite ni utilisée sous quelque forme que ce soit et par aucun procédé, électronique ou mécanique, y compris la photocopie et les microfilms, sans l'accord écrit de la CEI ou du Comité national de la CEI du pays du demandeur.

Si vous avez des questions sur le copyright de la CEI ou si vous désirez obtenir des droits supplémentaires sur cette publication, utilisez les coordonnées ci-après ou contactez le Comité national de la CEI de votre pays de résidence.

IEC Central Office
3, rue de Varembe
CH-1211 Geneva 20
Switzerland
Email: inmail@iec.ch
Web: www.iec.ch

About the IEC

The International Electrotechnical Commission (IEC) is the leading global organization that prepares and publishes International Standards for all electrical, electronic and related technologies.

About IEC publications

The technical content of IEC publications is kept under constant review by the IEC. Please make sure that you have the latest edition, a corrigenda or an amendment might have been published.

- Catalogue of IEC publications: www.iec.ch/searchpub

The IEC on-line Catalogue enables you to search by a variety of criteria (reference number, text, technical committee,...). It also gives information on projects, withdrawn and replaced publications.

- IEC Just Published: www.iec.ch/online_news/justpub

Stay up to date on all new IEC publications. Just Published details twice a month all new publications released. Available on-line and also by email.

- Electropedia: www.electropedia.org

The world's leading online dictionary of electronic and electrical terms containing more than 20 000 terms and definitions in English and French, with equivalent terms in additional languages. Also known as the International Electrotechnical Vocabulary online.

- Customer Service Centre: www.iec.ch/webstore/custserv

If you wish to give us your feedback on this publication or need further assistance, please visit the Customer Service Centre FAQ or contact us:

Email: csc@iec.ch

Tel.: +41 22 919 02 11

Fax: +41 22 919 03 00

A propos de la CEI

La Commission Electrotechnique internationale (CEI) est la première organisation mondiale qui élabore et publie des normes internationales pour tout ce qui a trait à l'électricité, à l'électronique et aux technologies apparentées.

A propos des publications CEI

Le contenu technique des publications de la CEI est constamment revu. Veuillez vous assurer que vous possédez l'édition la plus récente, un corrigendum ou amendement peut avoir été publié.

- Catalogue des publications de la CEI: www.iec.ch/searchpub/cur_fut-f.htm

Le Catalogue en-ligne de la CEI vous permet d'effectuer des recherches en utilisant différents critères (numéro de référence, texte, comité d'études,...). Il donne aussi des informations sur les projets et les publications retirées ou remplacées.

- Just Published CEI: www.iec.ch/online_news/justpub

Restez informé sur les nouvelles publications de la CEI. Just Published détaille deux fois par mois les nouvelles publications parues. Disponible en-ligne et aussi par email.

- Electropedia: www.electropedia.org

Le premier dictionnaire en ligne au monde de termes électroniques et électriques. Il contient plus de 20 000 termes et définitions en anglais et en français, ainsi que les termes équivalents dans les langues additionnelles. Egalement appelé Vocabulaire Electrotechnique International en ligne.

- Service Clients: www.iec.ch/webstore/custserv/custserv_entry-f.htm

Si vous désirez nous donner des commentaires sur cette publication ou si vous avez des questions, visitez le FAQ du Service clients ou contactez-nous:

Email: csc@iec.ch

Tél.: +41 22 919 02 11

Fax: +41 22 919 03 00

INTERNATIONAL STANDARD

NORME INTERNATIONALE

BASIC EMC PUBLICATION
PUBLICATION FONDAMENTALE EN CEM

**Electromagnetic compatibility (EMC) –
Part 4-6: Testing and measurement techniques – Immunity to conducted
disturbances, induced by radio-frequency fields**

**Compatibilité électromagnétique (CEM) –
Partie 4-6: Techniques d'essai et de mesure – Immunité aux perturbations
conduites, induites par les champs radioélectriques**

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

COMMISSION
ELECTROTECHNIQUE
INTERNATIONALE

PRICE CODE
CODE PRIX

CP

CONTENTS

FOREWORD.....	4
INTRODUCTION.....	6
1 Scope and object.....	7
2 Normative references.....	7
3 Definitions.....	7
4 General.....	9
5 Test levels.....	10
6 Test equipment.....	10
6.1 Test generator.....	10
6.2 Coupling and decoupling devices.....	11
6.3 Verification of the common mode impedance at the EUT port of coupling and decoupling devices.....	14
6.4 Setting of the test generator.....	15
7 Test set-up for table-top and floor-standing equipment.....	16
7.1 Rules for selecting injection methods and test points.....	16
7.2 Procedure for CDN injection application.....	18
7.3 Procedure for clamp injection when the common-mode impedance requirements can be met.....	18
7.4 Procedure for clamp injection when the common-mode impedance requirements cannot be met.....	19
7.5 Procedure for direct injection.....	19
7.6 EUT comprising a single unit.....	20
7.7 EUT comprising several units.....	20
8 Test procedure.....	20
9 Evaluation of the test results.....	21
10 Test report.....	22
Annex A (normative) Additional information regarding clamp injection.....	34
Annex B (informative) Selection criteria for the frequency range of application.....	39
Annex C (informative) Guide for selecting test levels.....	41
Annex D (informative) Information on coupling and decoupling networks.....	42
Annex E (informative) Information for the test generator specification.....	46
Annex F (informative) Test set-up for large EUTs.....	47
Bibliography.....	50
Figure 1 – Rules for selecting the injection method.....	17
Figure 2 – Immunity test to RF conducted disturbances.....	24
Figure 3 – Test generator set-up.....	25
Figure 4 – Definition of the wave shapes occurring at the output of the EUT port of a coupling device (e.m.f. of test level 1).....	25
Figure 5 – Principle of coupling and decoupling.....	28

Figure 6 – Principle of coupling and decoupling according to the clamp injection method	28
Figure 7 – Details of set-ups and components to verify the essential characteristics of coupling and decoupling devices and the 150 Ω to 50 Ω adapters	30
Figure 8 – Set-up for level setting (see 6.4.1)	31
Figure 9 – Example of test set-up with a single unit system.....	32
Figure 10 – Example of a test set-up with a multi-unit system	33
Figure A.1 – Circuit for level setting set-up in a 50 Ω test Jig	35
Figure A.2 – The 50 Ω test jig construction	35
Figure A.3 – Construction details of the EM clamp	36
Figure A.4 – Concept of the EM clamp (electromagnetic clamp).....	37
Figure A.5 – Coupling factor of the EM clamp	37
Figure A.6 – General principle of a test set-up using Injection clamps	38
Figure A.7 – Example of the test unit locations on the ground plane when using injection clamps (top view)	38
Figure B.1 – Start frequency as function of cable length and equipment size	40
Figure D.1 – Example of a simplified diagram for the circuit of CDN-S1 used with screened cables (see 6.2.1)	43
Figure D.2 – Example of simplified diagram for the circuit of CDN-M1/-M2/-M3 used with unscreened supply (mains) lines (see 6.2.2.1)	43
Figure D.3 – Example of a simplified diagram for the circuit of CDN-AF2 used with unscreened non-balanced lines (see 6.2.2.3)	44
Figure D.4 – Example of a simplified diagram for the circuit of a CDN-T2, used with an unscreened balanced pair (see 6.2.2.2)	44
Figure D.5 – Example of a simplified diagram of the circuit of a CDN-T4 used with unscreened balanced pairs (see 6.2.2.2)	45
Figure D.6 – Example of a simplified diagram of the circuit of a CDN-T8 used with unscreened balanced pairs (see 6.2.2.2)	45
Figure F.1 – Example of large EUT test set-up with elevated horizontal ground reference plane	48
Figure F.2 – Example of large EUT test set-up with vertical ground reference plane.....	49
Table 1 – Test levels	10
Table 2 – Characteristics of the test generator.....	11
Table 3 – Main parameter of the combination of the coupling and decoupling device.....	11
Table B.1 – Main parameter of the combination of the coupling and decoupling device when the frequency range of test is extended above 80 MHz	39
Table E.1 – Required power amplifier output power to obtain a test level of 10 V	46

INTERNATIONAL ELECTROTECHNICAL COMMISSION

ELECTROMAGNETIC COMPATIBILITY (EMC) –

Part 4-6: Testing and measurement techniques – Immunity to conducted disturbances, induced by radio-frequency fields

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
- 5) IEC provides no marking procedure to indicate its approval and cannot be rendered responsible for any equipment declared to be in conformity with an IEC Publication.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 61000-4-6 has been prepared by subcommittee 77B: High-frequency phenomena, of IEC technical committee 77: Electromagnetic compatibility.

This standard forms part 4-6 of IEC 61000. It has the status of a basic EMC publication in accordance with IEC Guide 107, *Electromagnetic compatibility – Guide to the drafting of electromagnetic compatibility publications*.

This consolidated version of IEC 61000-4-6 consists of the second edition (2003) [documents 77B/377/FDIS and 77B/384/RVD], its amendment 1 (2004) [documents 77B/426/FDIS and 77B/431/RVD] and its amendment 2 (2006) [documents 77B/492/FDIS and 77B/502/RVD].

The technical content is therefore identical to the base edition and its amendments and has been prepared for user convenience.

It bears the edition number 2.2.

A vertical line in the margin shows where the base publication has been modified by amendments 1 and 2.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of the base publication and its amendments will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

Withdawn

iTeh Standards
(<https://standards.iteh.ai>)
Document Preview

<https://standards.iteh.ai/standards/iec/91785433-7885-40d2-8de0-629b7f8e82f8/iec-61000-4-6-2003>

<https://standards.iteh.ai/standards/iec/91785433-7885-40d2-8de0-629b7f8e82f8/iec-61000-4-6-2003>

INTRODUCTION

IEC 61000 is published in separate parts according to the following structure:

Part 1: General

General considerations (introduction, fundamental principles)
Definitions, terminology

Part 2: Environment

Description of the environment
Classification of the environment
Compatibility levels

Part 3: Limits

Emission limits
Immunity limits (in so far as they do not fall under the responsibility of the product committees)

Part 4: Testing and measurement techniques

Measurement techniques
Testing techniques

Part 5: Installation and mitigation guidelines

Installation guidelines
Mitigation methods and devices

Part 6: Generic standards

Part 9: Miscellaneous

Each part is further subdivided into several parts, published either as international standards or as technical specifications or technical reports, some of which have already been published as sections. Others will be published with the part number followed by a dash and a second number identifying the subdivision (example : 61000-6-1).

This part is an international standard which gives immunity requirements and test procedure related to conducted disturbances induced by radio-frequency fields.

ELECTROMAGNETIC COMPATIBILITY (EMC) –

Part 4-6: Testing and measurement techniques – Immunity to conducted disturbances, induced by radio-frequency fields

1 Scope and object

This part of IEC 61000-4 relates to the conducted immunity requirements of electrical and electronic equipment to electromagnetic disturbances coming from intended radio-frequency (RF) transmitters in the frequency range 9 kHz up to 80 MHz. Equipment not having at least one conducting cable (such as mains supply, signal line or earth connection) which can couple the equipment to the disturbing RF fields is excluded.

NOTE 1 Test methods are defined in this part for measuring the effect that conducted disturbing signals, induced by electromagnetic radiation, have on the equipment concerned. The simulation and measurement of these conducted disturbances are not adequately exact for the quantitative determination of effects. The test methods defined are structured for the primary objective of establishing adequate repeatability of results at various facilities for quantitative analysis of effects.

The object of this standard is to establish a common reference for evaluating the functional immunity of electrical and electronic equipment when subjected to conducted disturbances induced by radio-frequency fields. The test method documented in this part of IEC 61000 describes a consistent method to assess the immunity of an equipment or system against a defined phenomenon.

NOTE 2 As described in IEC Guide 107, this is a basic EMC publication for use by product committees of the IEC. As also stated in Guide 107, the IEC product committees are responsible for determining whether this immunity test standard should be applied or not, and if applied, they are responsible for determining the appropriate test levels and performance criteria. TC 77 and its sub-committees are prepared to co-operate with product committees in the evaluation of the value of particular immunity tests for their products.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050(161), *International Electrotechnical Vocabulary (IEV) – Chapter 161: Electromagnetic compatibility*

3 Definitions

For the purpose of this part of IEC 61000, the definitions given in IEC 60050(161) as well as the following definitions apply.

3.1 artificial hand

electrical network simulating the impedance of the human body under average operational conditions between a hand-held electrical appliance and earth

[IEV 161-04-27]

NOTE The construction should be in accordance with CISPR 16-1.

3.2 auxiliary equipment AE

equipment necessary to provide the equipment under test (EUT) with the signals required for normal operation and equipment to verify the performance of the EUT

3.3 clamp injection

clamp injection is obtained by means of a clamp-on “current” injecting device on the cable:

- **current clamp**: a transformer, the secondary winding of which consists of the cable into which the injection is made;
- **electromagnetic clamp** (EM clamp): injection device with combined capacitive and inductive coupling

3.4 common-mode impedance

ratio of the common mode voltage and the common-mode current at a certain port

NOTE This common mode impedance can be determined by applying a unity common mode voltage between the terminal(s) or screen of that port and a reference plane (point). The resulting common mode current is then measured as the vectorial sum of all currents flowing through these terminal(s) or screen (see also Figures 8a and 8b).

3.5 coupling factor

ratio given by the open-circuit voltage (e.m.f.) obtained at the EUT port of the coupling (and decoupling) device divided by the open-circuit voltage obtained at the output of the test generator

3.6 coupling network

electrical circuit for transferring energy from one circuit to another with a defined impedance

NOTE Coupling and decoupling devices can be integrated into one box (coupling and decoupling network (CDN)) or they can be in separate networks.

3.7 coupling/decoupling network CDN

electrical circuit incorporating the functions of both the coupling and decoupling networks

3.8 decoupling network

electrical circuit for preventing test signals applied to the EUT from affecting other devices, equipment or systems that are not under test

3.9 test generator

generator (RF generator, modulation source, attenuators, broadband power amplifier and filters) capable of generating the required test signal (see Figure 3)

3.10**electromotive force****e.m.f.**

voltage at the terminals of the ideal voltage source in the representation of an active element
[IEV 131-01-38:1978]

3.11**measurement result** **U_{mr}**

voltage reading of the measurement equipment

3.12**voltage standing wave ratio****VSWR**

ratio of a maximum to an adjacent minimum voltage magnitude along the line

4 General

The source of disturbance covered by this part of IEC 61000 is basically an electromagnetic field, coming from intended RF transmitters, that may act on the whole length of cables connected to installed equipment. The dimensions of the disturbed equipment, mostly a sub-part of a larger system, are assumed to be small compared with the wavelengths involved. The in-going and outgoing leads (e.g. mains, communication lines, interface cables) behave as passive receiving antenna networks because of their length, which can be several wavelengths.

Between those cable networks, the susceptible equipment is exposed to currents flowing "through" the equipment. Cable systems connected to an equipment are assumed to be in resonant mode ($\lambda/4$, $\lambda/2$ open or folded dipoles) and as such are represented by coupling and decoupling devices having a common-mode impedance of 150 Ω with respect to a ground reference plane. Where possible the EUT is tested by connecting it between two 150 Ω common-mode impedance connections: one providing an RF source and the other providing a return path for the current.

This test method subjects the EUT to a source of disturbance comprising electric and magnetic fields, simulating those coming from intentional RF transmitters. These disturbing fields (E and H) are approximated by the electric and magnetic near-fields resulting from the voltages and currents caused by the test set-up as shown in Figure 2a.

The use of coupling and decoupling devices to apply the disturbing signal to one cable at the time, while keeping all other cables non-excited, see Figure 2b, can only approximate the real situation where disturbing sources act on all cables simultaneously, with a range of different amplitudes and phases.

Coupling and decoupling devices are defined by their characteristics given in 6.2. Any coupling and decoupling device fulfilling these characteristics can be used. The coupling and decoupling networks in Annex D are only examples of commercially available networks.

5 Test levels

No tests are required for induced disturbances caused by electromagnetic fields coming from intentional RF transmitters in the frequency range 9 kHz to 150 kHz.

Table 1 – Test levels

Frequency range 150 kHz – 80 MHz		
Level	Voltage level (e.m.f.)	
	U_0 dB(µV)	U_0 V
1	120	1
2	130	3
3	140	10
X ^a	Special	
^a X is an open level.		

The open-circuit test levels (e.m.f.) of the unmodulated disturbing signal, expressed in r.m.s., are given in Table 1. The test levels are set at the EUT port of the coupling devices, see 6.4.1. For testing of equipment, this signal is 80 % amplitude modulated with a 1 kHz sine wave to simulate actual threats. The effective amplitude modulation is shown in Figure 4. Guidance for selecting test levels is given in Annex C.

NOTE 1 IEC 61000-4-3 also defines test methods for establishing the immunity of electrical and electronic equipment against radiated electromagnetic energy. It covers frequencies above 80 MHz. Product committees may decide to choose a lower or higher transition frequency than 80 MHz (see Annex B).

NOTE 2 Product committees may select alternative modulation schemes.

6 Test equipment

6.1 Test generator

The test generator includes all equipment and components for supplying the input port of each coupling device with the disturbing signal at the required signal level at the required point. A typical arrangement comprises the following items which may be separate or integrated into one or more test instruments (see 3.9 and Figure 3):

- RF generator(s), G1, capable of covering the frequency band of interest and of being amplitude modulated by a 1 kHz sine wave with a modulation depth of 80 %. They shall have manual control (e.g., frequency, amplitude, modulation index) or in the case of RF synthesizers, they shall be programmable with frequency-dependent step sizes and dwell times;
- attenuator, T1, (typically 0 dB ... 40 dB) of adequate frequency rating to control the disturbing test source output level. T1 may be included in the RF generator and is optional;
- RF switch, S1, by which the disturbing test signal can be switched on and off when measuring the immunity of the EUT. S1 may be included in the RF generator and is optional;
- broadband power amplifier(s), PA, may be necessary to amplify the signal if the output power of the RF generator is insufficient;

- low-pass filters (LPF), and/or high-pass filters (HPF) may be necessary to avoid interference caused by (higher order or sub-) harmonics with some types of EUT, for example RF receivers. When required they shall be inserted in between the broadband power amplifier, PA, and the attenuator T2;
- attenuator, T2, (fixed ≥ 6 dB, $Z_o = 50 \Omega$), with sufficient power ratings. T2 is provided to reduce the mismatch from the power amplifier to the network.

NOTE T2 may be included in a coupling and decoupling network and can be left out if the output impedance of the broadband power amplifier remains within the specification under any load condition.

Characteristics of the test generator with and without modulation are given in Table 2.

Table 2 – Characteristics of the test generator

Output impedance	50 Ω
Harmonics and distortion	any spurious spectral line shall be at least 15 dB below the carrier level
Amplitude modulation	internal or external, 80 % \pm 5 % in depth 1 kHz \pm 10 % sine wave
Output level	sufficiently high to cover test level (see also Annex E)

6.2 Coupling and decoupling devices

Coupling and decoupling devices shall be used for appropriate coupling of the disturbing signal (over the entire frequency range, with a defined common-mode impedance at the EUT port) to the various cables connected to the EUT and for preventing applied test signals from affecting other devices, equipment and systems that are not under test.

The coupling and decoupling devices can be combined into one box (a coupling/ decoupling network, CDN) or can consist of several parts. The main coupling and decoupling device parameter, the common-mode impedance seen at the EUT-port, is specified in Table 3.

The preferred coupling and decoupling devices are the CDNs, for reasons of test reproducibility and protection of the AE. However, if they are not suitable or available, other injection methods can be used. Rules for selecting the appropriate injection method are given below and in 7.1.

Table 3 – Main parameter of the combination of the coupling and decoupling device

Parameter	Frequency band	
	0,15 MHz – 26 MHz	26 MHz – 80 MHz
$ Z_{ce} $	150 $\Omega \pm 20 \Omega$	150 $\Omega + 60 \Omega - 45 \Omega$

NOTE 1 Neither the argument of Z_{ce} nor the decoupling factor between the EUT port and the AE port are specified separately. These factors are embodied in the requirement that the tolerance of $|Z_{ce}|$ shall be met with the AE-port open or short-circuited to the ground reference plane.

NOTE 2 When clamp injection methods are used, without complying with the common-mode impedance requirements for the auxiliary equipment, the requirements of Z_{ce} may not be met. However, the injection clamps can provide acceptable test results when the guidance of 7.4 is followed.

6.2.1 Coupling/decoupling networks (CDNs)

These networks comprise the coupling and decoupling circuits in one box and can be used for specific unscreened cables e.g. CDN-M1, CDN-M2, CDN-M3, CDN-T2, CDN-T4, CDN-AF-2, see Annex D. Typical concepts of the coupling and the decoupling networks are given in Figures 5c and 5d. The networks shall not unduly affect the functional signals. Constraints on such effects may be specified in the product standards.

6.2.1.1 CDNs for power supply lines

Coupling/decoupling networks are recommended for all power supply connections. However, for high power (current ≥ 16 A) and/or complex supply systems (multi-phase or various parallel supply voltages) other injection methods may be selected.

The disturbing signal shall be coupled to the supply lines, using type CDN-M1 (single wire), CDN-M2 (two wires) or CDN-M3 (three wires), or equivalent networks (see Annex D). Similar networks can be defined for a 3-phase mains system. The coupling circuit is given in Figure 5c.

The performance of the CDN shall not be unduly degraded by saturation of the magnetic material due to current taken by the EUT. Wherever possible, the network construction should ensure that the magnetising effect of the forward current is cancelled by that due to the return current.

If in real installations the supply wires are individually routed, separate CDN-M1 coupling and decoupling networks shall be used and all input ports shall be treated separately.

If the EUT is provided with other earth terminals (e.g. for RF purposes or high leakage currents), they shall be connected to the ground reference plane:

- through the CDN-M1 when the characteristics or specification of the EUT permit. In this case, the (power) supply shall be provided through the CDN-M3 network;
- when the characteristics or specification of the EUT do not permit the presence of a CDN-M1 network in series with the earth terminal for RF or other reasons, the earth terminal shall be directly connected to the ground reference plane. In this case the CDN-M3 network shall be replaced by a CDN-M2 network to prevent an RF short circuit by the protective earth conductor. When the equipment was already supplied via CDN-M1 or CDN-M2 networks, these shall remain in operation.

Warning: The capacitors used within the CDNs bridge live parts. As a result, high leakage currents may occur and safety connections from the CDN to the ground reference plane are obligatory (in some cases, these connections may be provided by the construction of the CDN).

6.2.1.2 CDNs for unscreened balanced lines

For coupling and decoupling disturbing signals to an unscreened cable with balanced lines, a CDN-T2, CDN-T4 or CDN-T8 shall be used as coupling and decoupling network. Figures D.4, D.5 and D.6 in Annex D show these possibilities:

- CDN-T2 for a cable with 1 symmetrical pair (2 wires);
- CDN-T4 for a cable with 2 symmetrical pairs (4 wires);
- CDN-T8 for a cable with 4 symmetrical pairs (8 wires).